



## 1300MHz-1700MHz, 140W, 28V High Power RF LDMOS FETs

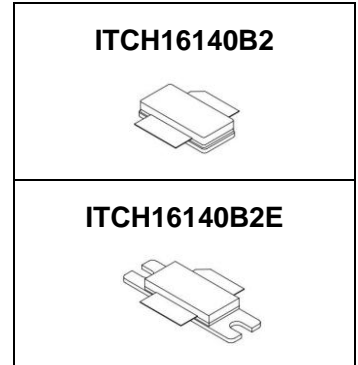
### Description

The ITCH16140B2 is a 140-watt, internally matched LDMOS FET, designed for multicarrier WCDMA/PCS/DCS/LTE base station and ISM applications with frequencies from 1300 to 1700 MHz. It Can be used in Class AB/B and Class C for all typical cellular base station modulation formats.

•Typical Performance (On Innegration fixture with device soldered):

VDD = 28 Volts, I<sub>DQ</sub> = 800 mA, Pulse CW, Pulse Width=12 us, Duty cycle=10% .

Frequency	G <sub>p</sub> (dB)	P <sub>-1dB</sub> (dBm)	η <sub>D</sub> @P <sub>-1</sub> (%)	P <sub>-3dB</sub> (dBm)	η <sub>D</sub> @P <sub>-3</sub> (%)
1390 MHz	19	51.5	56	52.5	59
1450 MHz	19.5	51	55	52.2	59
1529 MHz	18.5	50.2	55	51.2	59



### Features

- High Efficiency and Linear Gain Operations
- Integrated ESD Protection
- Internally Matched for Ease of Use
- Excellent thermal stability, low HCI drift
- Large Positive and Negative Gate/Source Voltage Range for Improved Class C Operation
- Pb-free, RoHS-compliant

**Table 1. Maximum Ratings**

Rating	Symbol	Value	Unit
Drain--Source Voltage	V <sub>DSS</sub>	70	Vdc
Gate--Source Voltage	V <sub>GS</sub>	-10 to +10	Vdc
Operating Voltage	V <sub>DD</sub>	+32	Vdc
Storage Temperature Range	T <sub>stg</sub>	-65 to +150	°C
Case Operating Temperature	T <sub>c</sub>	+150	°C
Operating Junction Temperature	T <sub>j</sub>	+225	°C

**Table 2. Thermal Characteristics**

Characteristic	Symbol	Value	Unit
Thermal Resistance, Junction to Case T <sub>C</sub> = 85°C, T <sub>J</sub> =200°C, DC test	R <sub>θJC</sub>	0.45	°C/W

**Table 3. ESD Protection Characteristics**

Test Methodology	Class
Human Body Model (per JESD22--A114)	Class 2

**Table 4. Electrical Characteristics** (TA = 25°C unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
<b>DC Characteristics</b> Drain-Source Breakdown Voltage (V <sub>GS</sub> =0V; I <sub>D</sub> =100uA)	V <sub>DSS</sub>	65			V



Zero Gate Voltage Drain Leakage Current ( $V_{DS} = 28\text{ V}$ , $V_{GS} = 0\text{ V}$ )	$I_{DSS}$			10	$\mu\text{A}$
Gate--Source Leakage Current ( $V_{GS} = 6\text{ V}$ , $V_{DS} = 0\text{ V}$ )	$I_{GSS}$			1	$\mu\text{A}$
Gate Threshold Voltage ( $V_{DS} = 28\text{ V}$ , $I_D = 600\text{ uA}$ )	$V_{GS(th)}$		1.6		V
Gate Quiescent Voltage ( $V_{DD} = 28\text{ V}$ , $I_{DQ} = 800\text{ mA}$ , Measured in Functional Test)	$V_{GS(Q)}$	2.2	2.7	3.2	V

**Functional Tests (In Innogrations demo, 50 ohm system) :**  $V_{DD} = 28\text{ Vdc}$ ,  $I_{DQ} = 800\text{ mA}$ ,  $f = 1450\text{ MHz}$ , Pulse CW, Pulse Width=12 us, Duty cycle=10% .

Power Gain	$G_p$		19.5		dB
Drain Efficiency@P3dB	$\eta_D$		59		%
1 dB Compression Point	$P_{-1dB}$		51		dBm
3dB Compression Point	$P_{-3dB}$		52.2		dBm
Input Return Loss	IRL		-7		dB

**Load Mismatch (In Innogrations Test Fixture, 50 ohm system):**  $V_{DD} = 28\text{ Vdc}$ ,  $I_{DQ} = 800\text{ mA}$ ,  $f = 1500\text{ MHz}$

VSWR 10:1 at 140W pulse CW Output Power	No Device Degradation
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Reference Circuit of Test Fixture Assembly Diagram

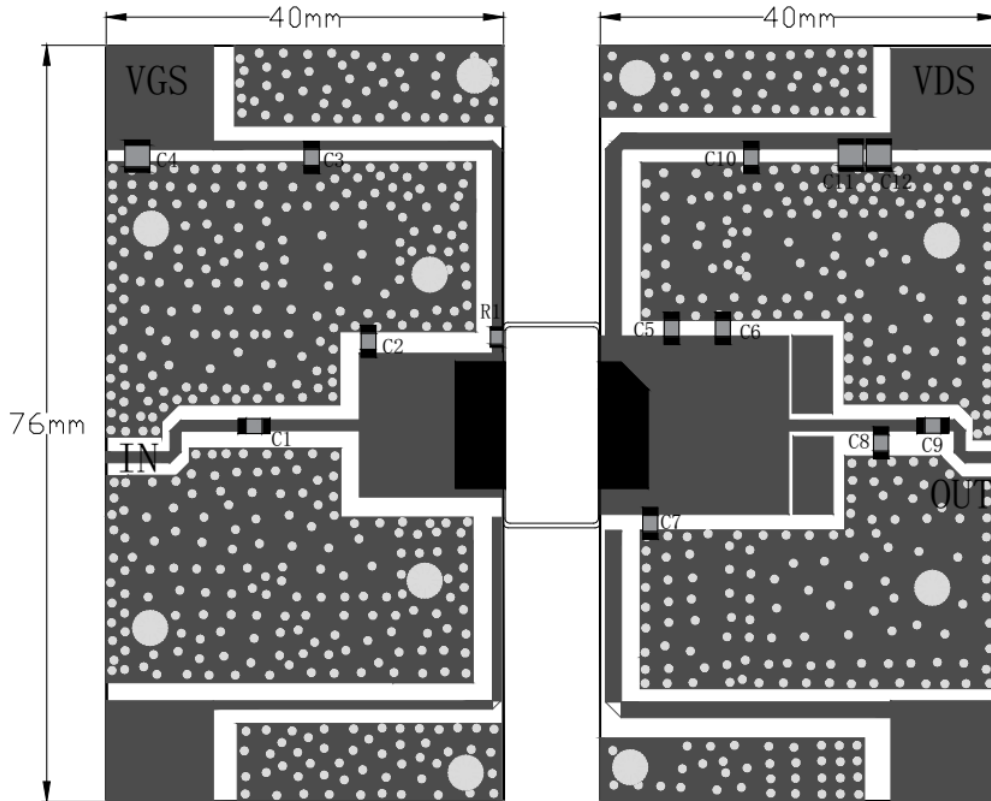


Figure 1. Test Circuit Component Layout

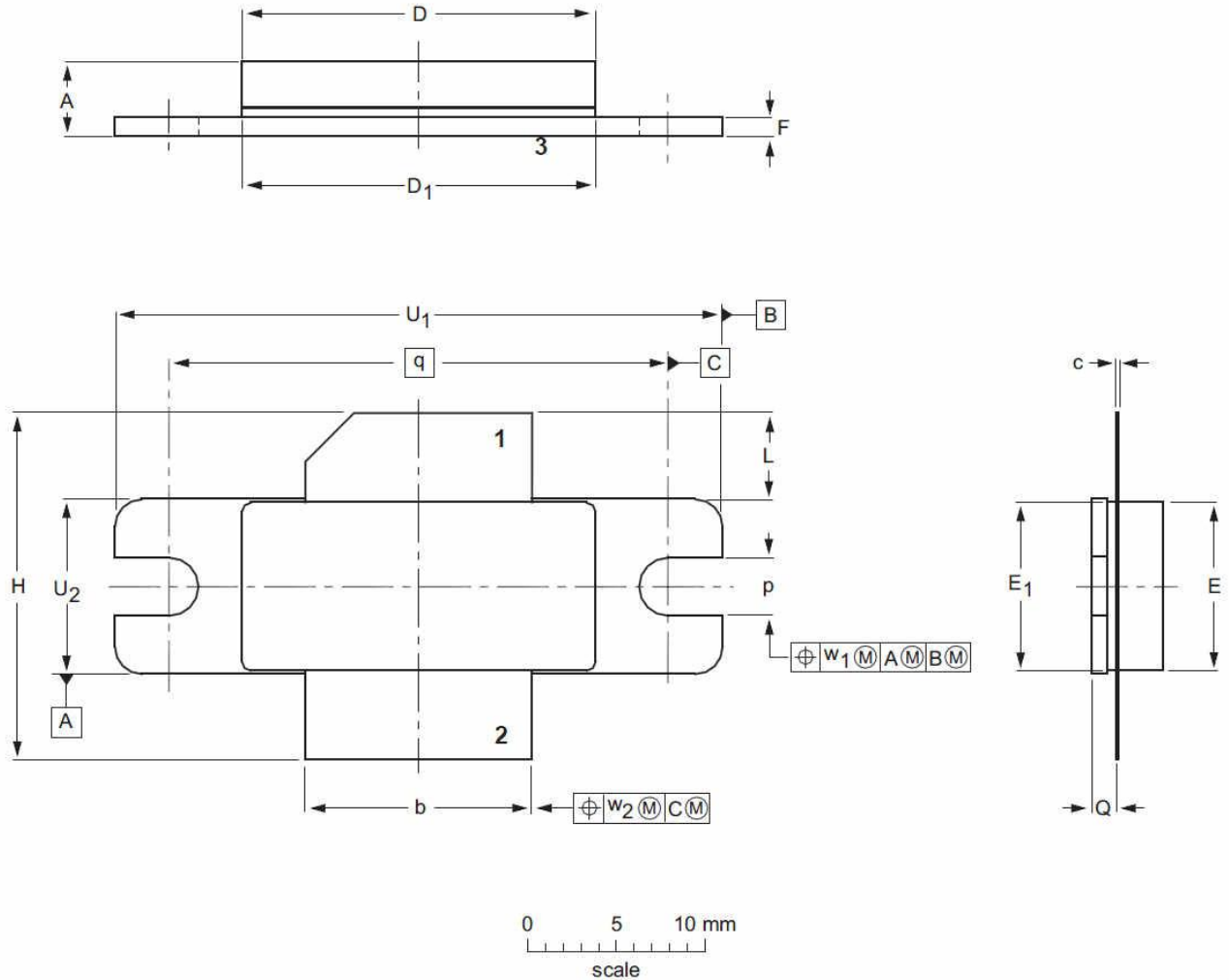
Table 5. Test Circuit Component Designations and Values

TBD.



## Package Outline

Flanged ceramic package; 2 mounting holes; 2 leads (1—DRAIN、2—GATE、3—SOURCE)

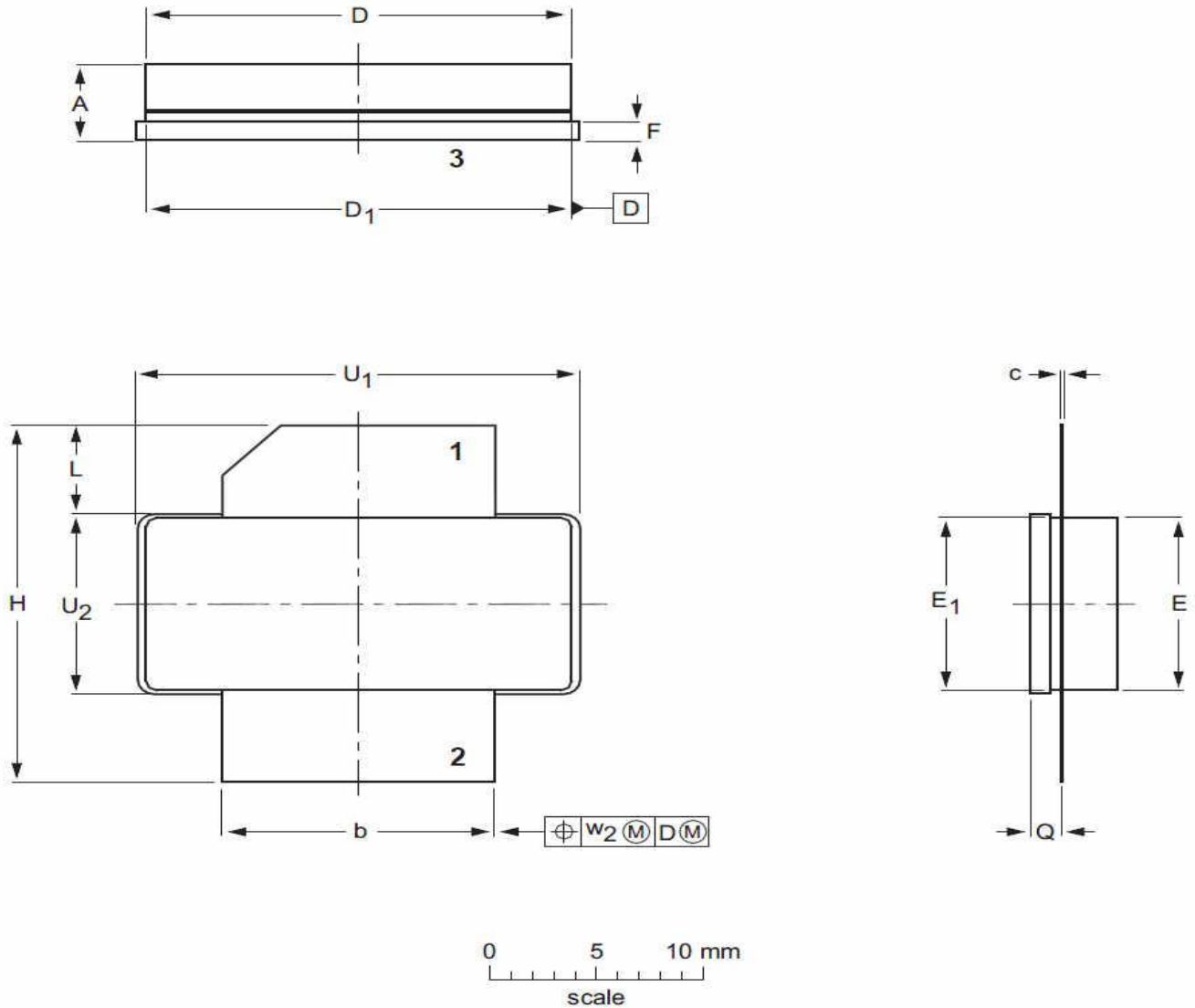


UNIT	A	b	c	D	D <sub>1</sub>	E	E <sub>1</sub>	F	H	L	p	Q	q	U <sub>1</sub>	U <sub>2</sub>	W <sub>1</sub>	W <sub>2</sub>
mm	4.72	12.83	0.15	20.02	19.96	9.50	9.53	1.14	19.94	5.33	3.38	1.70	27.94	34.16	9.91	0.25	0.51
	3.43	12.57	0.08	19.61	19.66	9.30	9.25	0.89	18.92	4.32	3.12	1.45		33.91	9.65		
inches	0.186	0.505	0.006	0.788	0.786	0.374	0.375	0.045	0.785	0.210	0.133	0.067	1.100	1.345	0.390	0.01	0.02
	0.135	0.495	0.003	0.772	0.774	0.366	0.364	0.035	0.745	0.170	0.123	0.057		1.335	0.380		

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	IEC	JEDEC	JEITA		
PKG-B2E					03/12/2013



Earless flanged ceramic package; 2 leads (1—DRAIN、2—GATE、3—SOURCE)



UNIT	A	b	c	D	D <sub>1</sub>	E	E <sub>1</sub>	F	H	L	Q	U <sub>1</sub>	U <sub>2</sub>	W <sub>2</sub>
mm	4.72	12.83	0.15	20.02	19.96	9.50	9.53	1.14	19.94	5.33	1.70	20.70	9.91	0.25
	3.43	12.57	0.08	19.61	19.66	9.30	9.25	0.89	18.92	4.32	1.45	20.45	9.65	
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	0.135	0.495	0.003	0.772	0.774	0.366	0.364	0.035	0.745	0.170	0.057	0.805	0.380	

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PKG-B2					03/12/2013



## Revision history

Table 6. Document revision history

Date	Revision	Datasheet Status
2017/01/23	Rev 1.0	Preliminary Datasheet

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